



# ECA TCM

Eddy current testing with sensor arrays for large-area inspection



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## Eddy current testing with sensor arrays for large-area inspection



**Eddy current testing with sensor arrays.** When the areas to be scanned are large, conventional eddy current inspection can be very time-consuming. Plus, there's the risk that manual probe guidance will leave some areas uninspected. The ECA module makes it possible to run both large-area and shape-matched array probes. This permits large areas to be scanned both quickly and comprehensively.

Array probes consist of several individual sensors arranged in a row inside a housing, for example. Connecting multiple sensors together in this way allows a larger area to be scanned at the resolution of each individual sensor.

### YOUR ADVANTAGES AT A GLANCE

**Large-area testing:** with arrays of up to 512 probe elements in parallel

**Easy handling:** automatic detection of probes and setting of relevant hardware parameters

**Localization of defects:** spatially resolved eddy current data for positionally accurate defect detection

**Enhanced visualization:** C-scan data now available in 3D view for improved defect assessment and interpretation

**100% documentation:** eddy current images can be saved as PNG or PDF

### NORMS

**DIN EN ISO 15548:** Standard defining performance characteristics and verification of eddy current testing instruments to ensure reliable and reproducible measurements.

# ACCESSORIES



## STANDARD TCM ARRAY PROBES

Versatile Eddy Current Array Probes for Efficient Surface Inspection



## HIGH-RESOLUTION ARRAY PROBE

High-resolution Eddy Current Array probe for the precise detection and localization of the smallest surface defects



## TCM STANDARD PROBES

Flexible probe solutions for precise eddy current inspection with the TCM



## TCM POSITION ENCODER

Precise Position Tracking for Flexible Eddy Current Inspections



## RECALIBRATION OF MOBILE PRODUCTS

Recalibration guarantees the accuracy and quality of your test and measurement values



## REFERENCE CRACK STANDARD - FLAT (PLATE)

Artificial crack defect standard for setting and verifying test sensitivity



## REFERENCE DEFECT STANDARDS - BOREHOLE

Reference defects for calibration of inspection systems using rotating probes



## SIGMA TEST PROBES

Flexible conductivity probes for precise testing of non-ferromagnetic metals



## TCM DOCKING STATION

From mobile inspection device to full workstation setup



## TCM SHOULDER STRAP

For comfortable hands-free operation of the TCM during mobile inspection tasks



## TCM SPARE BATTERY

Extend the operating time of your TCM and stay productive even during long inspection workflows.



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**Headquarters**

**Institut Dr. Foerster GmbH & Co. KG**

In Laisen 70  
72766 Reutlingen  
Germany

+49 7121 140 0  
[info@foerstergroup.com](mailto:info@foerstergroup.com)

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